Notice of References Cited Application/Control No. 10/756,757 Applicant(s)/Patent Under Reexamination MATSUTANI ET AL. Examiner Anh T. Mai Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

| | | Daywar at Niverban | Dete | | |
|---|---|--|-----------------|--------------------|----------------|
| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
| * | Α | US-2003/0052767 | 03-2003 | Yamanobe et al. | 336/232 |
| * | В | US-6,198,375 | 03-2001 | Shafer, Timothy M. | 336/225 |
| * | С | US-6,707,367 | 03-2004 | Castaneda et al. | 336/200 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | н | US- | | | |
| | 1 | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | JP0408306570A | 11-1996 | Japan | Tanaka et al. | H01F41/10 |
| | 0 | | | | | |
| | Р | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | s | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | w | |
| | x | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.